

Ty J Prosa

List of Publications by Year in descending order

Source: <https://exaly.com/author-pdf/8064010/publications.pdf>

Version: 2024-02-01

10
papers

473
citations

1937685

4
h-index

1588992

8
g-index

10
all docs

10
docs citations

10
times ranked

686
citing authors

#	ARTICLE	IF	CITATIONS
1	Study of LEAP® 5000 Deadtime and Precision via Silicon Pre-Sharpended-Microtipâ„¢ Standard Specimens. <i>Microscopy and Microanalysis</i> , 2022, 28, 1019-1037.	0.4	2
2	Al ₂ O ₃ Grain Boundary Segregation in a Thermal Barrier Coating on a Ni-Based Superalloy. <i>Microscopy and Microanalysis</i> , 2022, 28, 1453-1462.	0.4	2
3	Compositional boundary layers trigger liquid unmixing in a basaltic crystal mush. <i>Nature Communications</i> , 2019, 10, 4821.	12.8	20
4	Understanding Conditions Affecting Background in Atom Probe Tomography with Implications for Analysis of Hydrogen. <i>Microscopy and Microanalysis</i> , 2018, 24, 1028-1029.	0.4	1
5	Modern Focused-Ion-Beam-Based Site-Specific Specimen Preparation for Atom Probe Tomography. <i>Microscopy and Microanalysis</i> , 2017, 23, 194-209.	0.4	77
6	Evolution of Atom Probe Data Collection Toward Optimized and Fully Automated Acquisition. <i>Microscopy and Microanalysis</i> , 2017, 23, 616-617.	0.4	3
7	Effects of detector dead-time on quantitative analyses involving boron and multi-hit detection events in atom probe tomography. <i>Ultramicroscopy</i> , 2015, 159, 101-111.	1.9	73
8	Developing detection efficiency standards for atom probe tomography. , 2014, , .		10
9	Local Electrode Atom Probe Tomography. , 2013, , .		267
10	ATOM PROBE TOMOGRAPHY FOR MICROELECTRONICS. <i>Materials and Energy</i> , 2011, , 407-477.	0.1	18